

**SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017**

**AND**

**ANSI/NCSL Z540-1-1994 (R2002)**

**Bowman Analytics, Inc.**

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**CALIBRATION**

Valid to: **November 21, 2024**

Certificate Number: **L2213**

**Length – Dimensional Metrology**

| Parameter/Equipment   | Range                          | Expanded Uncertainty of Measurement (+/-) | Reference Standard, Method, and/or Equipment |
|---|--------------------------------|---|--|
| Coating Thickness Measuring Equipment and Coating Thickness Standards | (0.1 to 3 000) $\mu\text{in}$  | 3.5 % of reading                          | ASTM B568 (X-Ray)                            |
|   | (100 to 2 000) $\mu\text{in}$  | 4.9 % for Eddy Current                    | ASTM E376 (Eddy Current)                     |
|   | (100 to 60 000) $\mu\text{in}$ | 6.2 % for Magnetic Induction              | ASTM B499 (Magnetic Induction)               |

**Mass and Mass Related**

| Parameter/Equipment              | Range         | Expanded Uncertainty of Measurement (+/-) | Reference Standard, Method, and/or Equipment |
|----------------------------------|---------------|---|--|
| Composition – NiP <sup>1</sup>   | (1 to 99) wt% | 0.62 %                                    | ASTM B568 (X-Ray)                            |
| Composition – Alloy <sup>1</sup> | (1 to 99) wt% | 1.68 %                                    |  |

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 ( $k=2$ ), corresponding to a confidence level of approximately 95%.

Notes:

1. Weight percentage applied unless otherwise indicated.
2. This scope is formatted as part of a single document including Certificate of Accreditation No. L2213.



R. Douglas Leonard Jr., VP, PILR SBU